

10/517772

DT05 PCT/PTO SHEET 1 OF 27, DEC 2004

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 263878US2PCT	SERIAL NO. 101517772 New U.S. PCT Application Based on PCT/JP03/08146		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Kenji FUKUDA, et al.					
		FILING DATE Herewith 12/27/04		GROUP 2812			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
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	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
/WL/	AO	11-297712	10/29/99	JP(English abstract only)			NO
/WL/	AP	11-31691	02/02/99	JP(English abstract only)			NO
/WL/	AQ	2000-252461	09/14/00	JP(English abstract only)			NO
/WL/	AR	11-74263	03/16/99	JP(English abstract only)			NO
/WL/	AS	10-50701	02/20/98	JP(English abstract only)			NO
/WL/	AT	00/13236	03/09/00	WO			NO
/WL/	AU	9-199497	07/31/97	JP(English abstract only)			NO
/WL/	AV	10-112460	04/28/98	JP(English abstract only)			NO
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ	<input type="checkbox"/> Additional References sheet(s) attached					
Examiner	/Walter Lindsay Jr/			Date Considered 09/27/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 263878US2PCT	SERIAL NO. 10/517,772		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Kenji FUKUDA, et al.					
		FILING DATE December 27, 2004		GROUP 2812			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/WL/	AA	6 759 684	07/06/04	FUKUDA, Kenji et al.			
/WL/	AB	6 764 963	07/20/04	FUKUDA, Kenji et al.			
/WL/	AC	6 812 102	11/02/04	FUKUDA, Kenji et al.			
	AD						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
					YES	NO	
/WL/	AO	2000-252461	09/14/00	JP (with English abstract & computer generated translation)			NO
/WL/	AP	11-031691	02/02/99	JP (with English abstract & computer generated translation)			NO
/WL/	AQ	09-199497	07/31/97	JP (with English abstract & computer generated translation)			NO
/WL/	AR	10-112460	04/28/98	JP (with English abstract & computer generated translation)			NO
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/WL/	AW	OGINO, Shinji et al. "Channel Doped SiC-MOSFETs", Materials Science Forum, vols. 338-342, pages 1101-1104 2000					
/WL/	AX	FUKUDA, K. et al. "Effect of oxidation method and post-oxidation annealing on interface properties of metal-oxide-semiconductor structures formed on n-type 4H-SiC C(0001) face", Applied Physics Letters, vol. 77, no. 6, pages 866-868 2000					
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner	/Walter Lindsay Jr/				Date Considered 09/27/2007		
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08/28/07

	Docket No.: 263878US2PCT	Serial No.: 10/517,772
Inventor: Kenji FUKUDA, et al.		
LIST OF RELATED CASES CITED BY APPLICANT UNDER 37 CFR 1.56	Filing Date: July 12, 2005	Group: 2812

LIST OF RELATED CASES

<u>Examiner Initial</u>	<u>Docket No.</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent App. Publication No.</u>	<u>Inventor or Applicant</u>
/WL/	263878US2PCT*	10/517,772	07/12/05	2005-0245034	FUKUDA, et al.
/WL/	307205US2PCT	11/718,036	04/26/07		YATSUO, et al.

Examiner Date Considered
/Walter Lindsay Jr/ 09/27/2007

*Present Application; listed for information

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